

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ELM-1 Cont. 15APPLICATION NO.
10/766,629

JUL 21 2004

INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANT
Glenn J. LeedyCONFIRMATION NO.
3771FILING DATE
January 27, 2004GROUP
1765

U.S. PATENT DOCUMENTS

EXAMINE R INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>TTN</i>	Re. 34,893	04/04/95	Fujii et al.	257	419	
	2,915,722	12/01/59	Foster	336	115	
	3,202,948	08/24/65	Farrand	336	115	
	3,559,282	02/02/71	Lesk	438	113	
	3,560,364	02/02/71	Burkhardt	324	207.12	
	3,602,982	09/07/71	Emmasingel	29	577	
	3,615,901	10/26/71	Medicus	148	11.5 R	
	3,716,429	02/13/73	Napoli et al.	156	17	
	3,777,227	12/14/73	Krishna et al.	257	578	
	3,868,565	02/25/75	Kuipers	324	207.26	
	3,922,705	11/25/75	Yerman	357	26	
	3,997,381	12/14/76	Wanlass	156	3	
	4,070,230	01/24/78	Stein	156	657	
	4,131,985	01/02/79	Greenwood et al.	29	580	
	4,142,004	02/27/79	Hauser, Jr. et al.	438	792	
	4,251,909	02/24/81	Hoeberechts	29	580	
	4,262,631	04/21/81	Kubacki	118	723MP	
	4,394,401	07/19/83	Shioya et al.	427	574	
	4,401,986	08/30/83	Trenkler et al.	340	870.32	
	4,416,054	11/22/83	Thomas et al.	29	572	
	4,539,068	09/03/85	Takagi et al.	156	614	
	4,585,991	04/29/86	Reid et al.	324	158 P	
	4,612,083	09/16/86	Yasumoto et al.	156	633	
	4,617,160	10/14/86	Belanger et al.	264	40.1	
	4,618,397	10/21/86	Shimizu et al.	156	628	
	4,618,763	10/21/86	Schmitz	250	211R	
	4,663,559	05/05/87	Christensen	313	336	
	4,684,436	08/04/87	Burns et al.	216	65	
<i>TTN</i>	4,693,770	09/15/87	Hatada	156	151	

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FORM PTO-1449

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ELM-1 Cont. 15APPLICATION NO.
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TTN	4,702,336	10/27/87	Maeda et al.	180	197	
	4,702,936	10/27/87	Seibert et al.	427	583	
	4,706,166	11/10/87	Go	361	403	
	4,721,938	01/26/88	Stevenson	338	4	
	4,761,681	08/02/88	Reid	357	68	
	4,784,721	11/15/88	Holmen et al.	156	647	
	4,810,673	03/07/89	Freeman	438	386	
	4,825,277	04/25/89	Mattox et al.	257	639	
	4,857,481	08/15/89	Tam et al.	438	619	
	4,924,589	05/15/90	Leedy	438	6	
	4,940,916	07/10/90	Borel et al.	313	306	
	Re B14,940,916	11/26/96	Borel et al.	315	306	
	4,950,987	08/21/90	Vranish et al.	324	207.23	
	4,952,446	08/18/90	Lee et al.	428	220	
	4,954,865	09/04/90	Rokos	257	378	
	4,957,882	09/18/90	Shinomiya	438	65	
	4,965,415	10/23/90	Young et al.	200	83 N	
	4,966,663	10/30/90	Mauger	205	656	
	4,994,735	02/19/91	Leedy	324	158	
	5,008,619	04/16/91	Keogh et al.	324	207.17	
	5,010,024	04/23/91	Allen et al.	438	659	
	5,020,219	06/04/91	Leedy	29	846	
	5,034,685	07/23/91	Leedy	324	158 F	
	5,070,026	12/03/91	Greenwald et al.	437	3	
	5,071,510	12/10/91	Findler et al.	156	647	
	5,098,865	03/24/92	Machado et al.	438	788	
	5,103,557	04/14/92	Leedy	29	832	
	5,110,373	05/05/92	Mauger	148	33.2	
	5,111,278	05/05/92	Eichelberger	357	75	
	5,116,777	05/26/92	Chan et al.	438	234	
	5,130,894	07/14/92	Miller	361	393	
TTN	5,132,244	07/21/92	Roy	438	477	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Glenn J. Leedy	CONFIRMATION NO. 3771
		FILING DATE January 27, 2004	GROUP 1765

7/17/05	5,151,775	09/29/92	Hadwin	357	80	
	5,156,909	10/20/92	Henager, Jr. et al.	428	334	
	5,203,731	04/20/93	Zimmerman	445	24	
	5,225,771	07/06/93	Leedy	324	158	
	5,236,118	08/17/93	Bower et al.	228	193	
	5,262,351	11/16/93	Bureau et al.	437	183	
	5,270,261	12/14/93	Bertin et al.	437	209	
	5,273,940	12/28/93	Sanders	437	209	
	5,274,270	12/28/93	Tuckerman	257	758	
	5,279,865	01/18/94	Chebi et al.	427	574	
	5,284,796	02/08/94	Nakanishi et al.	437	183	
	5,323,035	06/21/94	Leedy	257	48	
	5,324,687	06/28/94	Wojnarowski	437	225	
	5,354,695	10/11/94	Leedy	438	411	
	5,363,021	11/08/94	MacDonald	315	366	
	5,385,909	01/31/95	Nelson et al.	514	291	
	5,385,632	01/31/95	Goossen	156	630	
	5,420,458	05/30/95	Shimoji	257	622	
	5,424,920	06/13/95	Miyake	361	735	
	5,426,072	06/20/95	Finnila	437	208	
	5,426,363	06/20/95	Akagi et al.	324	239	
	5,432,444	07/11/95	Yasohama et al.	324	240	
	5,432,729	07/11/95	Carson et al.	365	63	
	5,434,500	07/18/95	Hauck et al.	324	67	
	5,451,489	09/19/95	Leedy	430	313	
	5,453,404	09/26/95	Leedy	437	203	
	5,457,879	10/17/95	Gurtler et al.	29	895	
	5,476,813	12/19/95	Naruse	437	132	
	5,489,554	02/06/96	Gates	437	208	
	5,502,667	03/26/96	Bertin et al.	365	51	
	5,512,397	04/30/96	Leedy	430	30	
7/17/05	5,527,645	06/18/96	Pati et al.	430	5	

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	APPLICANT Glenn J. Leedy	CONFIRMATION NO. 3771
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TTN	5,529,829	06/25/96	Koskenmaki et al.	428	167	
	5,534,465	07/09/96	Frye et al.	437	209	
	5,555,212	09/10/96	Toshiaki et al.	365	200	
	5,563,084	10/08/96	Ramm et al.	437	51	
	5,571,741	11/05/96	Leedy	437	51	
	5,580,687	12/03/96	Leedy	430	5	
	5,581,498	12/03/96	Ludwig et al.	365	63	
	5,582,939	12/10/96	Pierrat	430	5	
	5,583,688	12/10/96	Hornbeck	359	291	
	5,592,007	01/07/97	Leedy	257	347	
	5,592,018	01/07/97	Leedy	257	619	
	5,595,933	01/21/97	Heijboer	439	20	
	5,606,186	02/25/97	Noda	257	226	
	5,627,112	05/06/97	Tennant et al.	438	113	
	5,629,137	05/13/97	Leedy	430	313	
	5,633,209	05/27/97	Leedy	435	228	
	5,637,536	06/10/97	Val	438	686	
	5,654,127	08/05/97	Leedy	430	315	
	5,654,220	08/05/97	Leedy	438	25	
	5,656,552	08/12/97	Hudak et al.	438	15	
	5,675,185	10/07/97	Chen et al.	257	774	
	5,694,588	12/02/97	Ohara et al.	395	566	
	5,725,995	03/10/98	Leedy	430	315	
	5,750,211	05/12/98	Weise et al.	427	579	
	5,760,478	06/02/98	Bozso et al.	257	777	
	5,773,152	06/30/98	Okonogi	428	446	
	5,786,116	07/28/98	Rolfson	430	5	
	5,793,115	08/11/98	Zavracky et al.	257	777	
	5,831,280	11/03/98	Ray	257	48	
	5,834,334	11/10/98	Leedy	438	107	
	5,840,593	11/24/98	Leedy	438	6	
TTN	5,856,695	01/05/99	Ito et al.	257	370	

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TW	5,868,949	02/09/99	Sotokawa et al.	216	18	
I	5,869,354	02/09/99	Leedy	438	110	
I	5,870,176	02/09/99	Sweatt et al.	355	53	
I	5,880,010	03/09/99	Davidson	438	455	
I	5,882,532	03/16/99	Field et al.	216	2	
I	5,902,118	05/11/99	Hübner	438	106	
I	5,915,167	06/22/99	Leedy	438	108	
I	5,946,559	08/31/99	Leedy	438	157	
I	5,985,693	11/16/99	Leedy	438	107	
I	5,998,069	12/07/99	Cutter et al.	430	5	
I	6,008,126	12/28/99	Leedy	438	667	
I	6,020,257	02/01/00	Leedy	438	626	
I	6,045,625	04/04/00	Houston	148	33.3	
I	6,084,284	07/04/00	Adamic, Jr.	257	506	
I	6,097,096	08/01/00	Gardner et al.	257	777	
I	6,133,640	10/17/00	Leedy	257	778	
I	6,194,245 B1	02/27/01	Tayanaka	438	57	
I	6,197,456 B1	03/06/01	Aleshin et al.	430	5	
I	6,208,545 B1	03/27/01	Leedy	365	51	
I	6,236,602 B1	05/22/01	Patti	365	201	
I	6,261,728 B1	07/17/01	Lin	430	30	
I	6,288,561 B1	09/11/01	Leedy	324	760	
TW	6,294,909 B1	09/25/01	Leedy	324	207.17	

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TW	WO 98/19337	05/1998	PCT	H01L	21/44		
I	GB 2,215,168	09/1989	UK	G09G	1/00		
I	EP 0 189 976	08/1986	EPO	H01L	31/18		
I	EP 0 731 525	09/1996	EPO	H01P	5/00		
I	2641129	12/1988	France	H01L	39/04		
TW	JP 60-74643	04/1985	Japan			ABST	

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7/14/03

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JP 02-082564	03/1990	Japan	ABST
JP 04-083371	03/1992	Japan	ABST
JP 04-107964	04/1992	Japan	ABST
JP 402027600A	01/1990	Japan	ABST

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TTN	"IC Tower Patent: Simple Technology Receives Patent on the IC Tower, a Stacked Memory Technology," http://www.simpletech.com/whatsnew/memory/@60824.htm (1998).
	Alloert, K., et al., "A Comparison Between Silicon Nitride Films Made by PCVD of N ₂ -SiH ₄ /Ar and N ₂ -SiH ₄ /He," <i>Journal of the Electrochemical Society</i> , Vol. 132, No. 7, pp. 1763-1766, (July 1985).
	Hendricks, et al., "Polyquinoline Coatings and Films: Improved Organic Dielectrics for IC's and MCM's," <i>Eleventh IEEE/CHMT International Electronics Manufacturing Technology Symposium</i> , pp. 361-265 (1991).
	Knolle, W.R., et al., "Characterization of Oxygen-Doped, Plasma-Deposited Silicon Nitride," <i>Journal of the Electrochemical Society</i> , Vol. 135, No. 5, pp. 1211-1217, (May 1988).
	Nguyen, S.V., "Plasma Assisted Chemical Vapor Deposited Thin Films for Microelectronic Applications," <i>J. Vac. Sci. Technol.</i> Vol. B4, No. 5, pp.1159-1167, (Sep/Oct. 1986).
	Olmer, et al., "Intermetal Dielectric Deposition by Plasma Enhanced Chemical Vapor Deposition," <i>Fifth IEEE/CHMT International Electronic Manufacturing Technology Symposium - Design-to-Manufacturing Transfer Cycle</i> , pp. 98-99 (1988).
	Runyan, W.R., "Deposition of Inorganic Thin Films," <i>Semiconductor Integrated Circuit Processing Technology</i> , p. 142 (1990).
	Sze, S.M., "Surface Micromachining," <i>Semiconductor Sensors</i> , pp. 58-63 (1994).
	Vossen, John L., "Plasma-Enhanced Chemical Vapor Deposition," <i>Thin Film Processes II</i> , pp. 536-541 (1991).
TTN	Wolf, Stanley, "Basics of Thin Films," <i>Silicon Processing for the VLSI Era</i> , pp. 115, 192, 193, and 199 (1986).

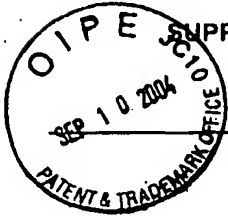
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ELM/001 Cont. 15APPLN. NO.
10/766,629APPLICANTS
Glenn J. LeedyCONF. NO.
3771FILING DATE
January 27, 2004GROUP ART UNIT
1765SUPPLEMENTAL INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	4,500,905	02/19/1985	Shibata	357	68	
	4,939,568	07/03/1990	Kato, et al.	357	75	
	4,892,753	01/09/1990	Wang, et al.	427	579	
	5,000,113	03/19/1991	Wang, et al.	118	723	
	5,240,458	08/31/1993	Linglain, et al.	464	63	
	5,259,247	11/09/1993	Bantien	73	718	
	RE 34,893	04/04/1995	Fujii, et al.	257	419	
	RE 36,623	03/21/2000	Wang, et al.	427	579	
	6,087,284	07/11/2000	Brix, et al.	501	69	
	6,518,073	02/11/2003	Momohara	438	4	12/10/2001

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	04-196,263	07/1992	Japan				

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EXAMINER INITIAL	
	Aboaf, J.A., "Stresses in SiO ₂ Films Obtained from the Thermal Decomposition of Tetraethylorthosilicate - Effect of Heat Treatment and Humidity," J. Electrochem. Soc.: Solid State Science; 116(12): 1732-1736 (Dec. 1969).
	Scheuerman, R.J., "Fabrication of Thin Dielectric Films with Low Internal Stresses," J. Vac. Sci. and Tech., 7(1): 143-146 (1970).
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	APPLICANTS Glenn J. Leedy	CONF. NO. 3771
	FILING DATE January 27, 2004	GROUP ART UNIT 1765

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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TJW	Trelchel, et al., "Planarized Low-Stress Oxide/Nitride Passivation for ULSI Devices," J. Phys IV, Colloq. (France), 1 (C2): 839-846 (1991).
	Krishnamoorthy, et al., "3-D Integration of MQW Modulators Over Active Submicron CMOS Circuits: 375 Mb/s Transimpedance Receiver-Transmitter Circuit," IEEE Photonics Technology Letters, 2(11): 1288-1290 (November 1995).
	Tielert, et al., "Benefits of Vertically Stacked Integrated Circuits for Sequential Logic," IEEE, XP-000704550, 121-124 (December 5, 1996).
	"Miniature Electron Microscopes Without Vacuum Pumps, Self-Contained, Microfabricated Devices with Short Working Distances, Enable Operation in Air," NASA Tech Briefs, 39-40 (1998).
TJW	Partial European Search Report for Application No. EP 02009643 (October 8, 2002).

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Sheet 1 of 1

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

SECOND SUPPLEMENTAL INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

ATTY. DOCKET NO.
ELM/001 Cont. 15

APPLN. NO.
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APPLICANTS
Glenn J. Leedy

CONF. NO.
3771

FILING DATE
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GROUP ART UNIT
1765

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TJN	4,897,708	01/30/90	Clements			
TJN	4,983,251	01/08/91	Haisma et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TJN	DE 32 33 195	03/17/83	Germany				
	JP S60-126871	07/06/85	Japan				
	JP S63-229862	09/26/88	Japan				
	EP 0 314 437	05/03/89	EPO				
	JP H01-199476	08/10/89	Japan				
	JP H03-284871	12/16/91	Japan				
	WO 92/03848	03/05/92	PCT				
	JP 04-076946	03/11/92	Japan				
TJN	WO 01/05366	01/25/01	PCT				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL	

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PTO/SB/08A (10-01)

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Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if known	
		Application Number	10/766,629
		Filing Date	January 27, 2004
		First Named Inventor	Glenn J. Leedy
		Art Unit	2818
Examiner Name	Quoc Dinh Hong		
Attorney Docket Number	ELM-1 CONT.15		
Sheet	1	of	1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
TDW		US-4,835,765	05/30/1989	Bergmans et al.	
I		US-4,919,749	04/24/1990	Mauger et al.	
I		US-5,144,142	09/01/1992	Fueki et al.	
TDW		US-5,262,341	11/16/1993	Fueki et al.	

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Examiner Initials	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Country Code ¹ - Number ² - Kind Code ³				
TDW		JP-127816	05-30-1991	Japan		
TDW		JP-174715	07-29-1991	Japan		

NON PATENT LITERATURE DOCUMENTS			
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PTO/SB/08A (10-01)

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Substitute for form 1449/PTO		INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Complete if known	
				Application Number	10/766,629 (Conf. No.: 3771)
		Filing Date	January 27, 2004		
		First Named Inventor	Glenn J. Leedy		
		Art Unit	2818		
		Examiner Name	Thinh T. Nguyen		
Sheet 1 of 1		Attorney Docket Number	ELM-1 CONT.15		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
TTN		6,230,233	05/08/2001	Lofgren et al.	
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		Country Code ¹ - Number ² - Kind Code ³				
TTN		JP S63-076484	04/06/1988	Suzuno et al.		
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		WO 03/078305	09/25/2003	Viefers et al.		
TTN						

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TTN		Sung, et al., "Well-aligned carbon nitride nanotubes synthesized in anodic alumina by electron cyclotron resonance chemical vapor deposition," Applied Physics Letters, Volume 74, Number 2, 197, 1999, January 11, 1999.	
TTN		Phys. Rev., B, Condens. Matter Mater. Phys. (USA), Physical Review B (Condensed Matter and Materials Physics), 15 March 2003, APS through AIP, USA.	

Examiner Signature		Date Considered	7/14/05
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Examiner

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